

Specification	AXX5032-2	Issue: 02	Date: 2006-03-18
Oscillator type :	Quartz Crystal Unit in SMD package 5.0x3.2 mm		RoHS compliant
	Resin sealed 2 pad		

Parameter	min.	typ.	max.	Unit	Condition
Frequency range	8.0		60	MHz	
Actual frequency f_0				MHz	
Crystal cut / Vibration mode	AT				
Load capacitance C_L	8 pF, 10 pF or Series				
Overtone	1				
Adjustment tolerance	$\pm 15 / \pm 30 / \pm 50 / \pm 100$			ppm	@ 25°C $\pm 5^\circ\text{C}$
Frequency stability				ppm	Overall (Note 1)
Frequency stability over temperature range	$\pm 10 \sim \pm 100$			ppm	See table below
operating temperature range (steady state)	0		+50	$^\circ\text{C}$	
	-10		+60	$^\circ\text{C}$	
	-20		+70	$^\circ\text{C}$	
	-40		+85	$^\circ\text{C}$	
long term (aging)			± 5	ppm	
Resonance resistance R_r			500	Ω	@ 8 ~ 9 MHz
			250	Ω	@ >9 ~ 9.5 MHz
			200	Ω	@ >9.5 ~ 10 MHz
			150	Ω	@ >10 ~ 12 MHz
			100	Ω	@ >12 ~ 16 MHz
			70	Ω	@ >16 ~ 30 MHz
			50	Ω	@ >30 ~ 60 MHz
Motional capacitance C_1				fF	
Static capacitance C_0			7	pF	
Drive level		50	500	μW	
Insulation resistance	500			M Ω	100 V DC
Storage temperature range	-40		+85	$^\circ\text{C}$	
Enclosure (see drawing)	5.0 x 3.2 x 1.1				IEC 61637
marking	Frequency (MHz) + Date Code				
Packing	Tape & Reel				IEC 60286-3

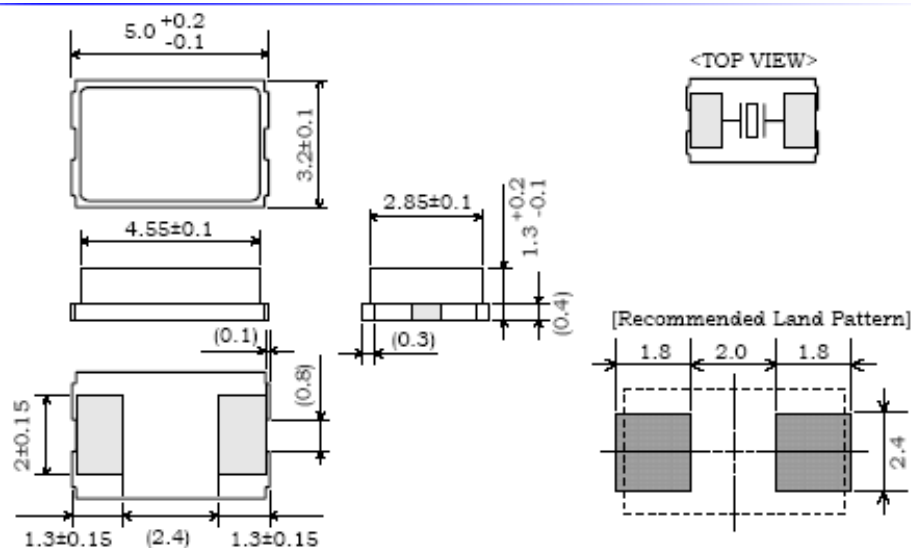
Notes:

- Overall frequency stability = initial tolerance + temp. stability + aging (1st year)
- Terminology and test conditions are according to IEC standard IEC60122-1, unless otherwise stated
- Measurement technique according to IEC 60444-5 or equivalent

Frequency vs. Temperature Stabilities

0° ~ +50°C	-10° ~ +60°C	-20° ~ +70°C	-40 ~ +85°C
± 10 ppm	± 15 ppm	± 20 ppm	± 30 ppm
± 30 ppm	± 30 ppm	± 30 ppm	± 50 ppm
± 50 ppm	± 50 ppm	± 50 ppm	± 100 ppm
± 100 ppm	± 100 ppm	± 100 ppm	

Enclosure drawing



Environmental conditions

Test	IEC 60068 Part ...	IEC 61178-1 clause ...	Test conditions
Visual inspection, dimensions		4.5 4.6	Enclosure styles as in IEC 60122-3, if applicable
Sealing tests	2-17	4.8.2	Gross leak: Test Qc, Fine leak: Test Qk
Solderability Resistance to soldering heat	2-20	4.8.3	Test Ta (235 ± 5)°C Method 1 Test Tb Method 1A, 5s
Shock	2-27	4.8.8	Test Ea, 3 x per axes 100g, 6 ms half-sine pulse
Bump	2-29	4.8.6	Test Eb, 4000 bumps per Axes, 40g, 6 ms
Free fall	2-32	4.8.9	Test Ed procedure 1, 2 drops from 1m height
Vibration, sinusoidal	2-6	4.8.7	Test Fc, 30 min per axes, 10 Hz - 55 Hz 0,75mm; 55 Hz - 1 kHz, 10g
Rapid change of temperature	2-14	4.8.5	Test Na, 10 cycles at extremes of operating temperature range
Dry heat	2-2	4.8.11	Test Ba, 16 h at upper temperature indicated by climatic category
Damp heat, cyclic	2-30	4.8.12	Test Db variant 1 severity b), 55°C/95% r.H., 6 cycles
Cold	2-1	4.8.13	Test Aa, 2 h at lower temperature indicated by climatic category
Climatic sequence	1-7	4.8.14	Sequence of 4.8.11, 4.8.12 (1 st cycle), 4.8.13, 4.8.12 (5 cycles)
Damp heat, steady state	2-3	4.8.15	Test Ca, 56 days
Endurance tests - ageing - extended aging		4.9.1 4.9.2	30 days @ 85°C 1000h, 2000h, 8000h @85°C